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# **Notice of References Cited**

Application/Control No. 09/911,613	Applicant(s)/Pater Reexamination CHUNG ET AL.	Applicant(s)/Patent Under Reexamination CHUNG ET AL.		
Examiner	Art Unit			
A. Sefer	2826	Page 1 of 1		

#### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,323,521	11-2001	Seo	257/347
	В	US-6,291,136	09-2001	Masutani et al	430/312
	С	US-2002/0066902	06-2002	Takatoku	257/72
	D	US-5,917,563	06-1999	Matsushima	349/38
	Е	US-6,358,759	03-2002	Hirabayashi	438/7
	F	US-2001/0024187	09-2001	Sato et al	345/98
	G	US-2002/0057394	05-2002	Takahashi et al	349/43
	н	US-2001/0040649	11-2001	Ozaki	349/43
	ı	US-2001/0020994	09-2001	Kaneko et al	349/147
	J	US-			
	к	US-		·	
	L	US-			
$\Box$	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-29053	01-2000	Japan	Masutani et al	
	0	JP 56-50537	05-1981	Japan	Hirose	
	Р	JP 10-282520	10-1998	Japan	Kasai et al	
	Q					
	R					
	s					
	Т					

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.